

EMB-A70M

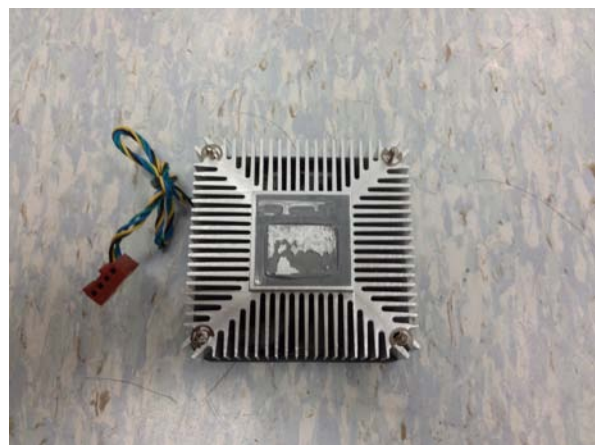
Thermal Image Analysis Report

Summary	<input checked="" type="checkbox"/> Pass <input type="checkbox"/> Fail <input type="checkbox"/> Pass with Deviation Comment: _____			
	Test Result Summary			
	Critical	Major	Minor	Enhancement
Defect Found	0	0	0	0
Defect Unsolved	0	0	0	0

Issue date	Approval	Test Engineer
_____	_____	_____
2013 / 07 / 09	Tom Lin	Jerry Chen

Sample Configuration & Quantity Under Test

- Model name : EMB-A70M A0.3
- CPU Board : EMB- A70M A0.3
- CPU : AMD R-460H APU with HD Graphics 2.00GHz
- Memory : DDR3 1066 / 4G / SEC K4B2G0846C
- 2.5" SATA HDD : HITACHI / HTS543216A7A384 / 2.5 SATA HDD / 160GB
- BIOS : EMB-A70M R1.0
- Test Software : Windows 7 / Run PassMark Burn In Test 7.0 Pro
- Power : AT Power
- CPU Cooler :



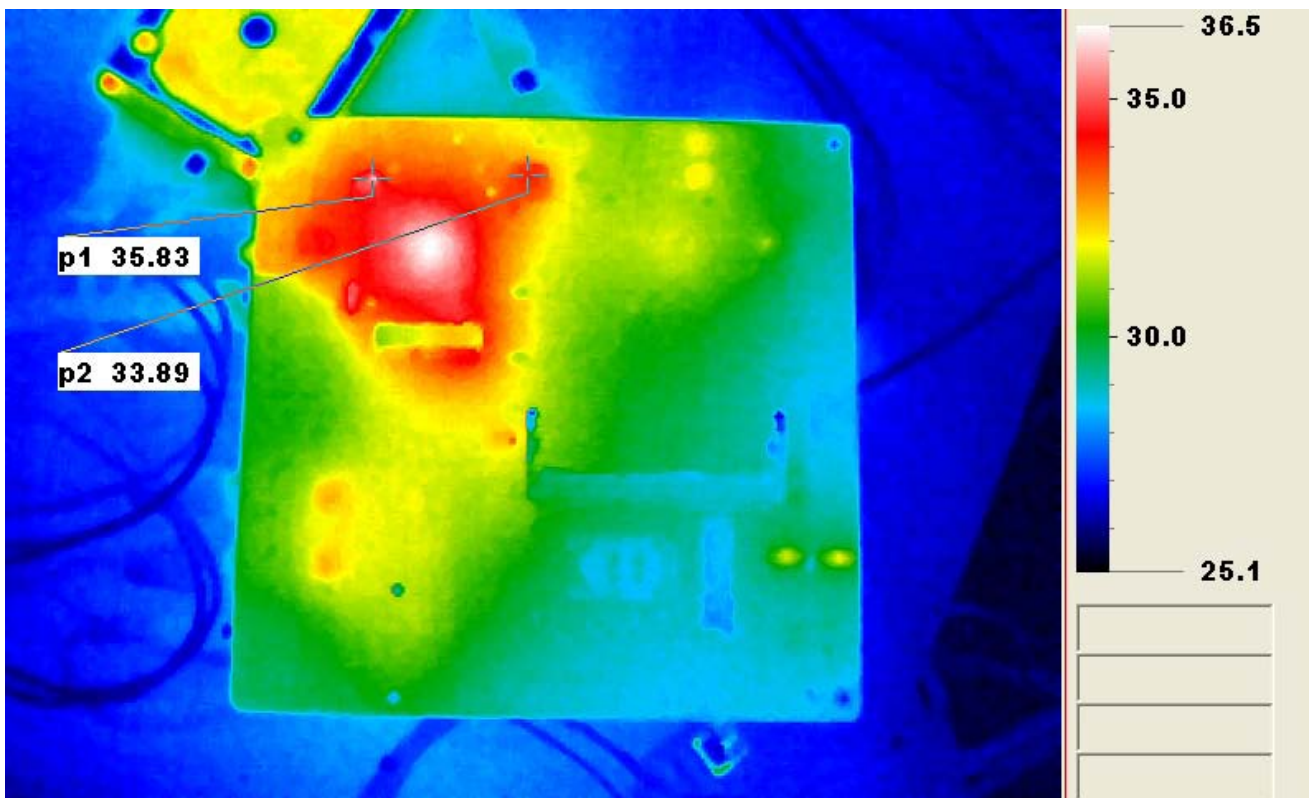
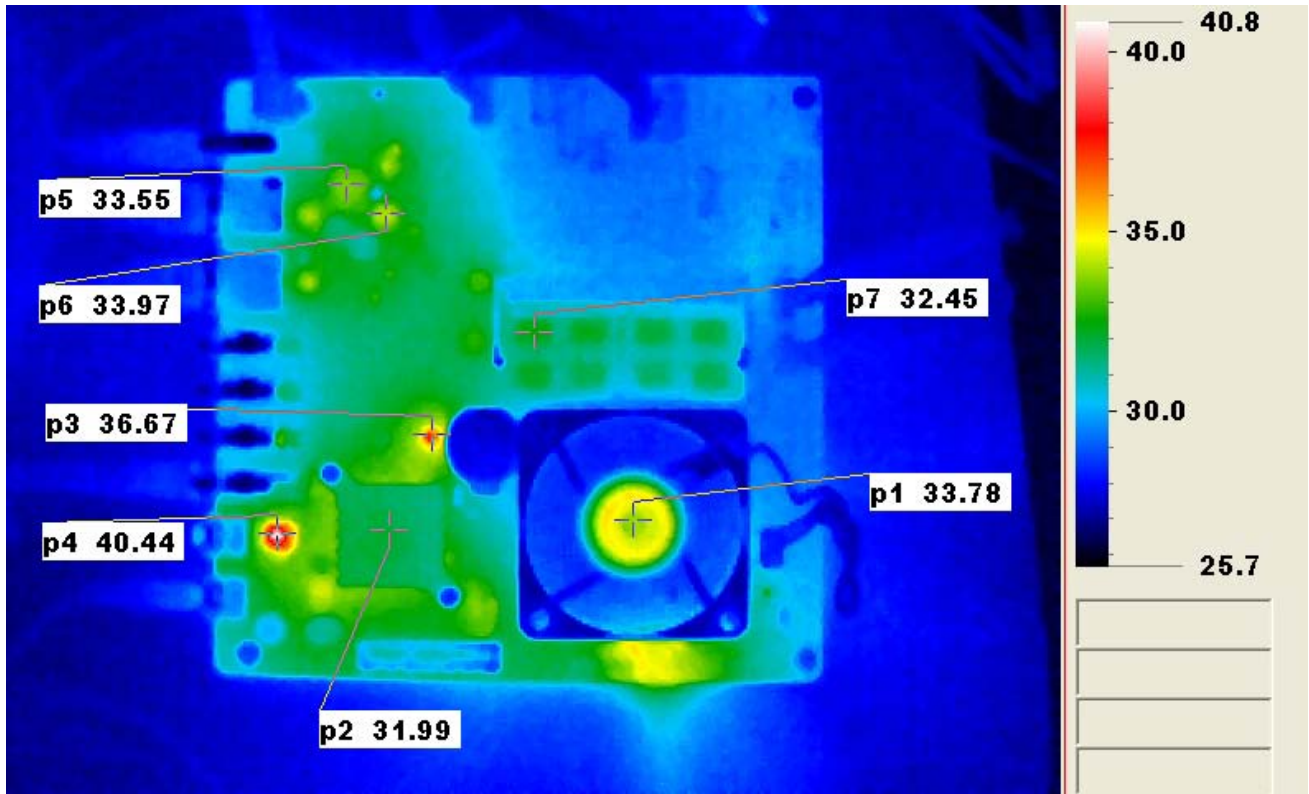
Thermal Image Analysis

1. Test Date: 2013-07-05
2. Test Product: EMB-A70M A0.3
3. Test Site: AAEON QE Dept.
4. Temperature Measurement:
 - 4.1. 40 Channel Thermal Recorder:
 - 4.1.1 YOKOGAWA Inc,
 - 4.2.2 Model: DA100-13-1D
Date of Calibration: 2012/10/08
Serial Number: 12A323190
 - 4.2. IR Scanner: Infrared Camera
 - 4.2.1 NEC Avio Infrared Technologies Co., Ltd.
 - 4.2.2 Model: Thermo GEAR G100W2-D
Date of Calibration: 2013/01/08
Serial Number: 1051444
5. Test Condition:

Test by DA-100: 25.1°C with CPU Cooler
6. Take Picture Time:

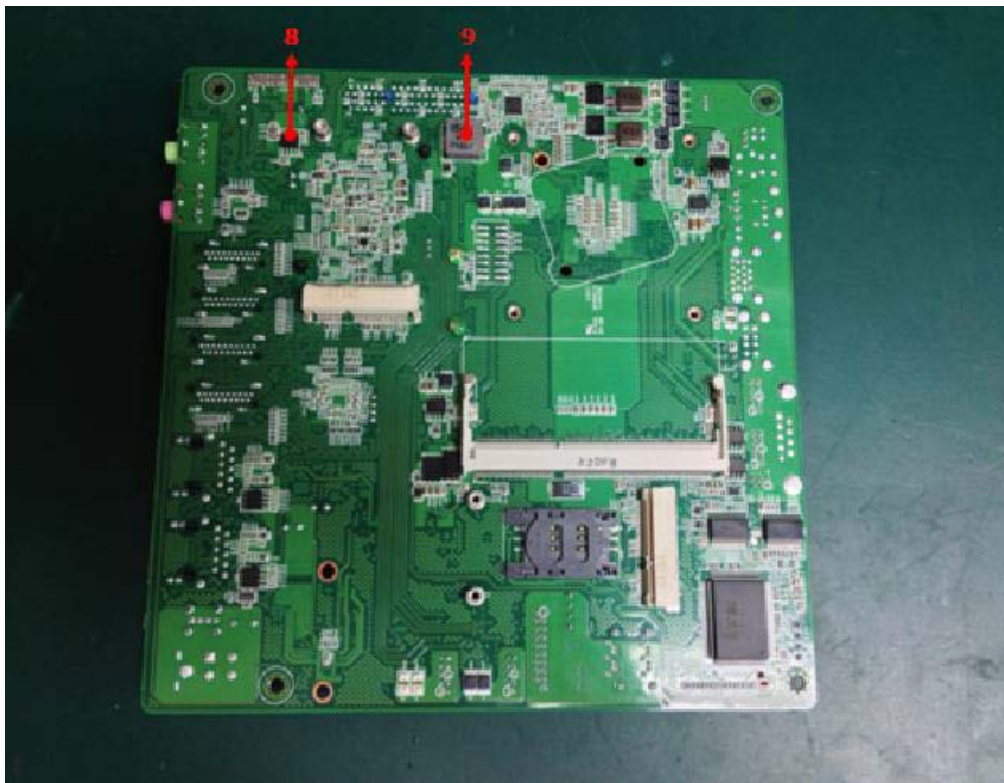
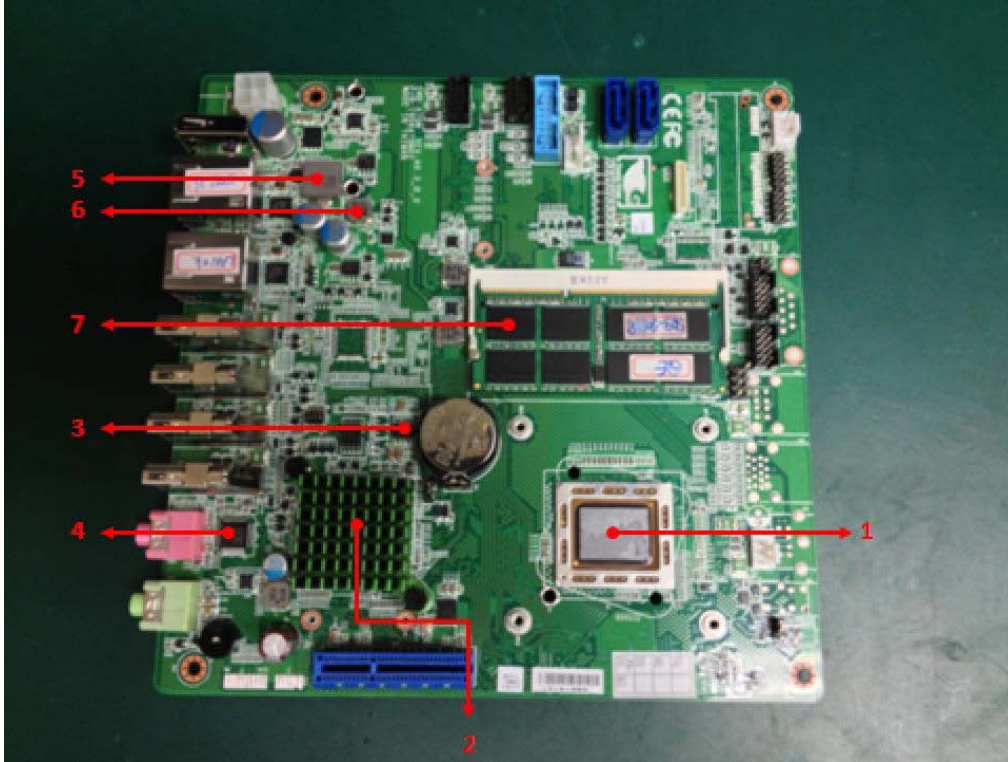
After power on 2 hours

Temperature Profile Test:
Component Side:



Terminal Recorder:

Measuring Thermal Couple Position :



Using YOKOGAWA / DARWIN DA100-100-13-1D test

Point	Position	Describe	Tc (*1) (°C)	Tm (*2) Measured Under		Note
				25.1°C	60°C	
1	U22	(TF)AMD APU.R-series.2.0GHz. 827P.RE460LSIE44HJE.R-460L	100	43.5	78.4	
2	U47	(TF) Hudson-M3 Fusion.AMD.A70M	105	33.6	68.5	
3	U46	(TF) Low-Voltage LDO Regulator.UPI.UP0104PSU8	100	35.5	70.4	
4	U61	(TF) 7.1+2 Channel Audio Codec. REALTEK.ALC892-CG	100.5	38.2	73.1	
5	L4	(TF)CYNTEC.PCMB104E-3R3MS	100	31.4	66.3	
6	L3	(TF) Panasonic.ETQP3W4R7WFN	125	32.2	67.1	
7		Memory chipset - 1	95	31.5	66.4	
8	Q72	(TF)PWR.Dual N-Channel MOSFET.SMD.SO-8.IR.IRF8313PbF	150	34.0	68.9	
9	L10	(TF)COIL. Panasonic.ETQP4LR56WFC	100	35.3	70.2	

Note(*):

1. "Tc" indicates the component's case maximum temperature value specified in its datasheet.
2. "Tm" indicates the measured Tc value under working environmental temperature within product specification.
3. Judgment Criteria:
 - Fail : $T_m > T_c + 5^\circ\text{C}$; The measured value is over specification plus margin.
 - Margin : $T_c + 5^\circ\text{C} > T_m > T_c - 10^\circ\text{C}$; The measured value is within specification with margin.
For FANLESS system application, it is strongly recommended to add thermal dissipation design for better reliability.
 - Pass : $T_m < T_c - 10^\circ\text{C}$; The measured value is with safety margin.
4. Defect NO. E120807LABDO